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Application/Control No.	Applicant(s)/Patent under Reexamination
10/750,864	HIRANO ET AL.
Examiner	Art Unit
Queenie Dehghan	1791

	SEARCHED		
Class	Subclass	Date	Examiner
65	412,419, 424-426 428	4/13/2007	QSD
Search	updated	11/1/2007	QSD
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING	SEARCH	STRATEGY	<u>') </u>
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